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January 2004

# FDZ204P

## P-Channel 2.5V Specified PowerTrench<sup>®</sup> BGA MOSFET

### General Description

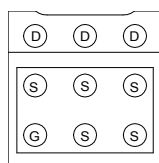
Combining Fairchild's advanced 2.5V specified PowerTrench process with state of the art BGA packaging, the FDZ204P minimizes both PCB space and  $R_{DS(ON)}$ . This BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultra-low profile packaging, low gate charge, and low  $R_{DS(ON)}$ .

### Applications

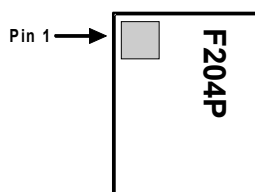
- Battery management
- Load switch
- Battery protection

### Features

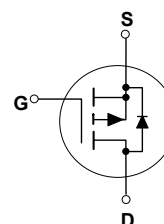
- -4.5 A, -20 V.  $R_{DS(ON)} = 45\text{ m}\Omega @ V_{GS} = -4.5\text{ V}$   
 $R_{DS(ON)} = 75\text{ m}\Omega @ V_{GS} = -2.5\text{ V}$
- Occupies only 4 mm<sup>2</sup> of PCB area. Less than 40% of the area of a SSOT-6
- Ultra-thin package: less than 0.80 mm height when mounted to PCB
- Ultra-low  $Q_g \times R_{DS(ON)}$  figure-of-merit.
- High power and current handling capability.



Bottom



Top



### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain-Source Voltage	-20	V
$V_{GSS}$	Gate-Source Voltage	±12	V
$I_D$	Drain Current – Continuous (Note 1a)	-4.5	A
	– Pulsed	-20	
$P_D$	Power Dissipation (Steady State) (Note 1a)	1.8	W
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	°C

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	67	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Ball (Note 1)	11	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	1	°C/W

### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
204P	FDZ204P	7"	8mm	3000 units

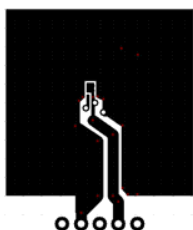
### Electrical Characteristics

T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-20			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		-17		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μA
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	V <sub>GS</sub> = -12 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	V <sub>GS</sub> = 12 V, V <sub>DS</sub> = 0 V			100	nA
<b>On Characteristics (Note 2)</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-0.6	-0.9	-1.5	V
ΔV <sub>GS(th)</sub> ΔT <sub>J</sub>	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		3		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -4.5 A V <sub>GS</sub> = -2.5 V, I <sub>D</sub> = -3.5 A V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -4.5 A, T <sub>J</sub> = 125°C		37 57 50	45 75 65	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -5 V, I <sub>D</sub> = -4.5 A		15		S
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V,		884		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		258		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			103		pF
<b>Switching Characteristics (Note 2)</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -6 V, I <sub>D</sub> = -1 A,		12	22	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>GS</sub> = -4.5 V, R <sub>GEN</sub> = 6 Ω		9	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			36	58	ns
t <sub>f</sub>	Turn-Off Fall Time			24	38	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -4.5 A,		9	13	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -4.5 V		2		nC
Q <sub>gd</sub>	Gate-Drain Charge			3		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-1.5	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -1.5 A (Note 2)		-0.76	-1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = -5.5 A,		25		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	d <sub>I</sub> /d <sub>t</sub> = 100 A/μs		26		nC

**Notes:**

- R<sub>θJA</sub> is determined with the device mounted on a 1 in<sup>2</sup> 2 oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. The thermal resistance from the junction to the circuit board side of the solder ball, R<sub>θJB</sub>, is defined for reference. For R<sub>θJC</sub>, the thermal reference point for the case is defined as the top surface of the copper chip carrier. R<sub>θJC</sub> and R<sub>θJB</sub> are guaranteed by design while R<sub>θJA</sub> is determined by the user's board design.



a) 67 °C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB

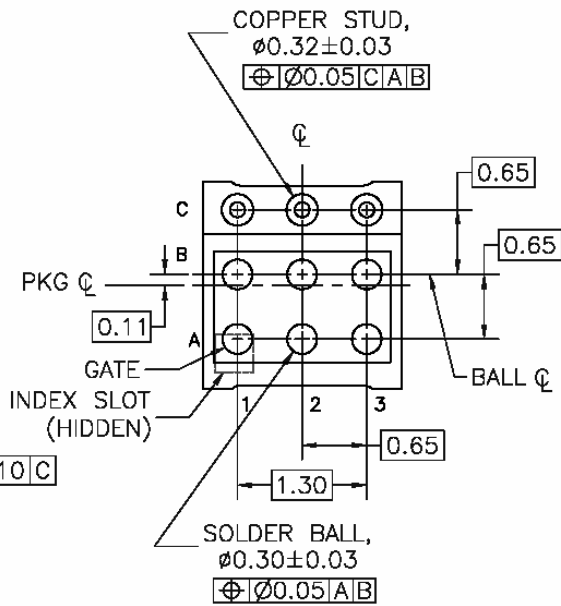
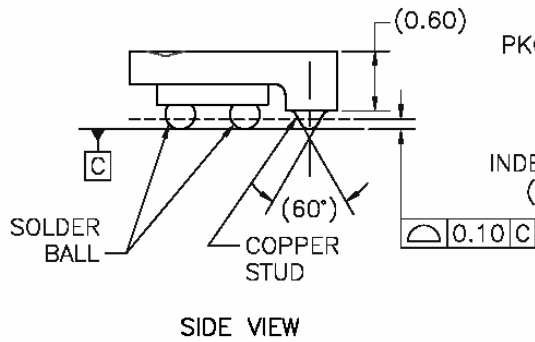
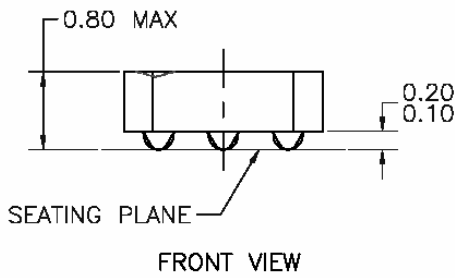
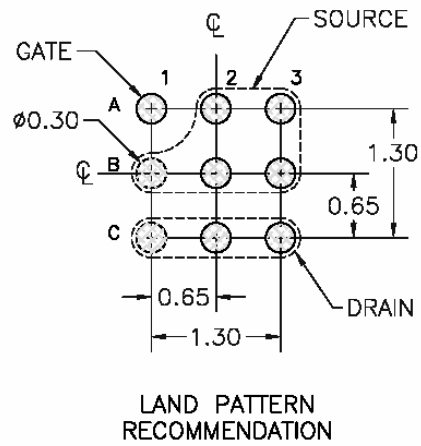
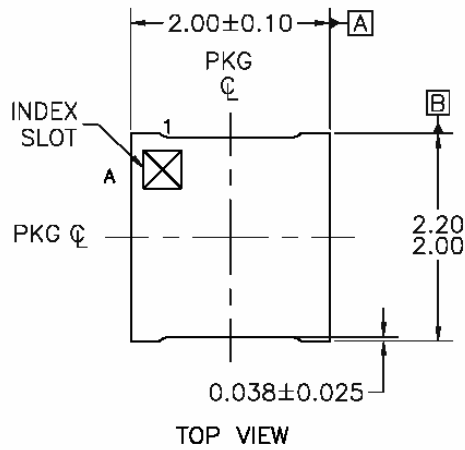


b) 155 °C/W when mounted on a minimum pad of 2 oz copper

Scale 1 : 1 on letter size paper

2. 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

**Dimensional Outline and Pad Layout**

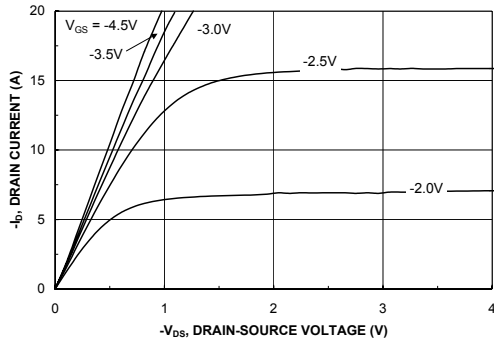


NOTES: UNLESS OTHERWISE SPECIFIED

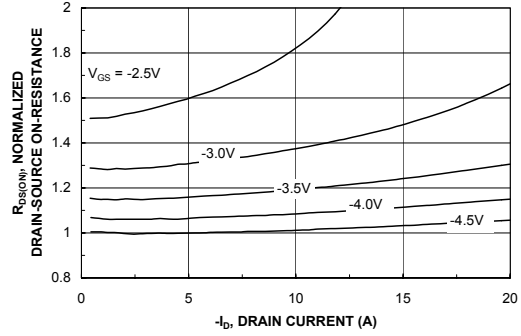
- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) NO JEDEC REGISTRATION REFERENCE AS OF JULY 1999.
- C) TERMINAL CONFIGURATION TABLE.

POSITION	DESIGNATION	TYPE
C1,C2,C3	DRAIN	COPPER STUD
A1	GATE	SOLDER BALL
A2,A3,B1,B2,B3	SOURCE	SOLDER BALL

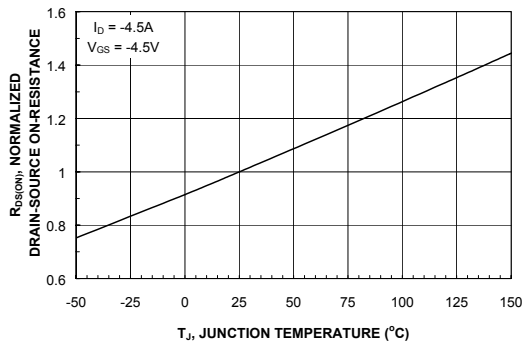
**Typical Characteristics**



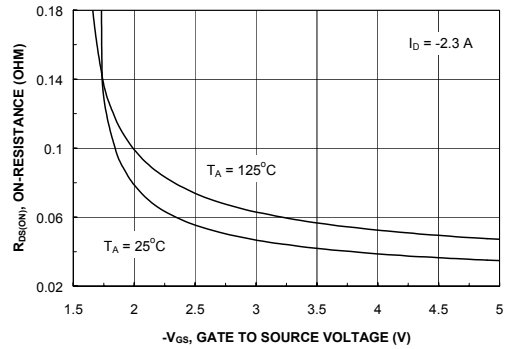
**Figure 1. On-Region Characteristics.**



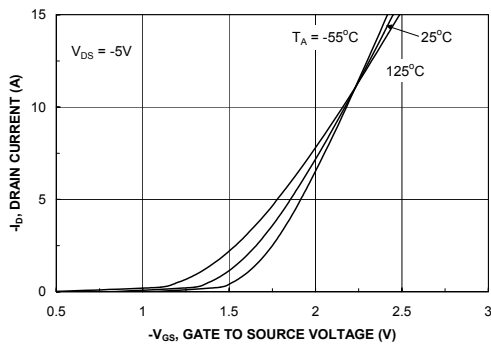
**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.**



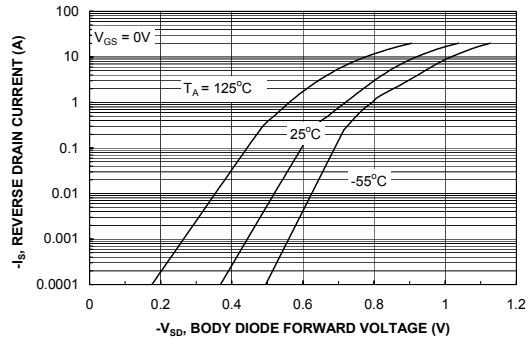
**Figure 3. On-Resistance Variation with Temperature.**



**Figure 4. On-Resistance Variation with Gate-to-Source Voltage.**

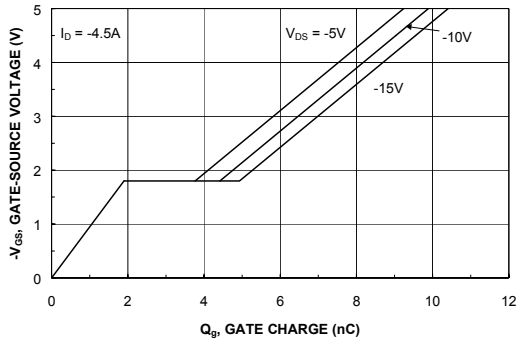


**Figure 5. Transfer Characteristics.**

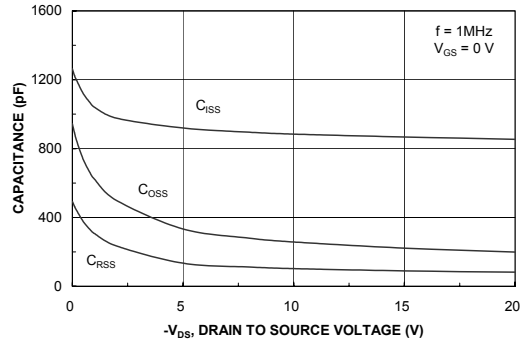


**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.**

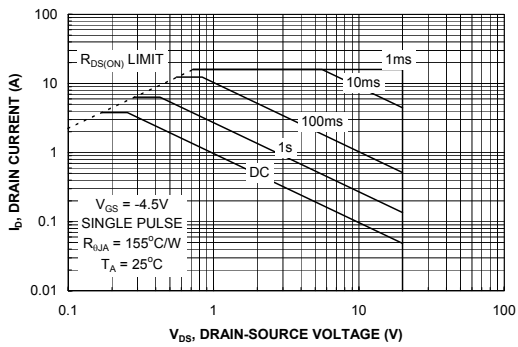
**Typical Characteristics**



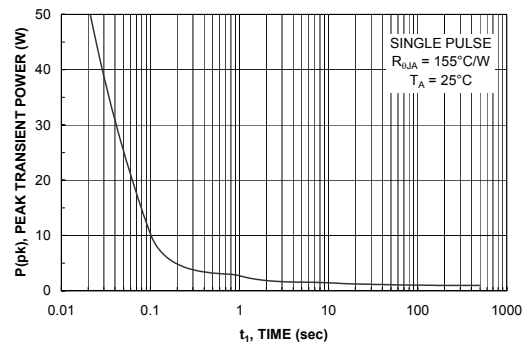
**Figure 7. Gate Charge Characteristics.**



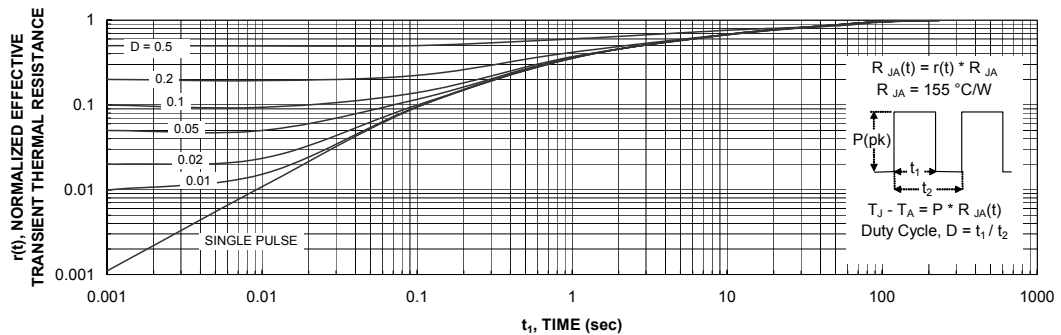
**Figure 8. Capacitance Characteristics.**



**Figure 9. Maximum Safe Operating Area.**



**Figure 10. Single Pulse Maximum Power Dissipation.**



**Figure 11. Transient Thermal Response Curve.**

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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